

Conference Agenda

Session

SES-04: Instrumentation and New Methods I

Time: Wednesday, 05/Feb/2025: 3:50pm - 5:10pm

Presentations

Exploring image quality improvements in high-speed dual threshold photon-counting micro-CT

Till Dreier¹, Spyridon Gkoumas²

¹Excillum AB, Sweden; ²DECTRIS Ltd., Switzerland

High-Energy Microtomography using Synchrotron Radiation at PETRA III / DESY

Felix Beckmann, Julian Moosmann, Joerg U. Hammel, Fabian Wilde

Helmholtz-Zentrum Hereon, Germany

Gulliver – A new kind of industrial CT

MICHAEL SALAMON¹, NILS REIMS¹, DIMITRI PRJAMKOV¹, DENNIS AK², MARKUS KRONENBERGER³, KATJA SCHLADITZ³, CLAUDIA REDENBACH⁴, SZYMON GRZESIAK⁴, CHRISTOPH DE SOUSA⁴, CATHERINA THIELE⁴, MATTHIAS PAHN⁴

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Correcting for focal spot drift in edge illumination X-ray phase contrast imaging

Nicholas Francken, Jonathan Sanctorum, Ben Huyge, Jan Sijbers, Jan De Beenhouwer

University of Antwerp, Belgium